

**Search Notes**

Application/Control No.

10/725,379

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under  
Reexamination

TOBITA ET AL.

Art Unit

2861

**SEARCHED**

Class	Subclass	Date	Examiner
347	68,70,72	12/20/2005	SWH
29	25/35	12/20/2005	SWH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east text search (see attached)	12/20/2005	SWH